MEASURE AND TAG THE CARRIER-ENVELOPE PHASE
OF YOUR LASER SYSTEM ON THE FLY

CEP·tag

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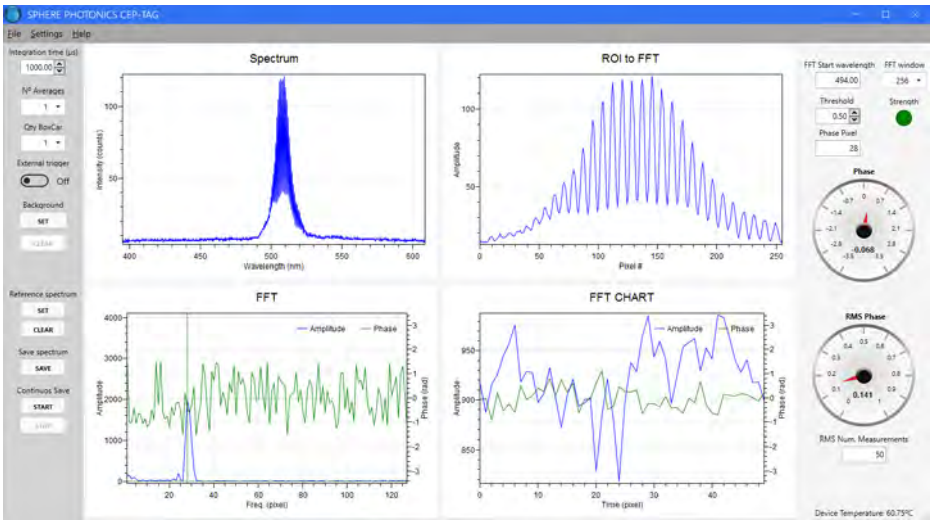
Understanding the carrier-envelope phase (CEP) offset is crucial in strong-field laser-matter interactions. Our CEP-tag system revolutionizes this application with its ability to deliver fast, single-shot measurements of the CEP offset in amplified laser pulses.

Leveraging the proven technique of f-2f interferometry, our system combines the second harmonic of the pulse's red edge with the blue edge of an octave-spanning spectrum for accessing the CEP.

Our cutting-edge solution features a photodiode array for accurate detection, and with the integration of Field-Programmable Gate Array (FPGA) electronics, it boasts the capability to measure CEP at an impressive rate of 130 kHz.

Embrace the precision of next-generation laser pulse analysis with the CEP-tag system



The CEP-tag's intuitive graphical user interface offers users rapid access to all essential measurement and control parameters for streamlined operation.

KEY FEATURES

- Online single-shot CEP measurement and tagging.
- Acquisition at up to 130 kHz.
- Integration with d-scan system for compact footprint

TECHNICAL SPECIFICATIONS	CEP-tag
Central wavelength	800 nm, 1030 nm [a]
Repetition rate	up to 130 kHz
Input polarization	Linear
Input aperture diameter	7 mm
Input energy	>10 µJ
Dimensions (WxLxH)	250 x 240 x 100 mm

(a) Other central wavelengths on request

Contact us to discuss customized solutions for different wavelength ranges, chirp ranges, input apertures, and more